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(57) Abstract :

The present disclosure relates to a system (100) for detecting defect in a product, the system includes an image capturing device (102) configured to capture one or more images of the product. A processor (104) configured to receive the images of the product, analyse the received images to extract a set of attributes from the images, classify the extracted set of attributes based on matching of the extracted set of attributes with a reference set of attributes and extract a set of values for the extracted set of attributes, wherein, based on a combination of classification of the extracted attributes and a deviation of the extracted set of values for the extracted set of attributes from a reference set of values, the processor is configured to determine and segment the product into a set of categories.

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